

LPP EUV Source Performance and Prospects for NGL in Mass Production of sub-20nm Devices

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October 2, 2012

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Leading the Light Generation.

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Introduction

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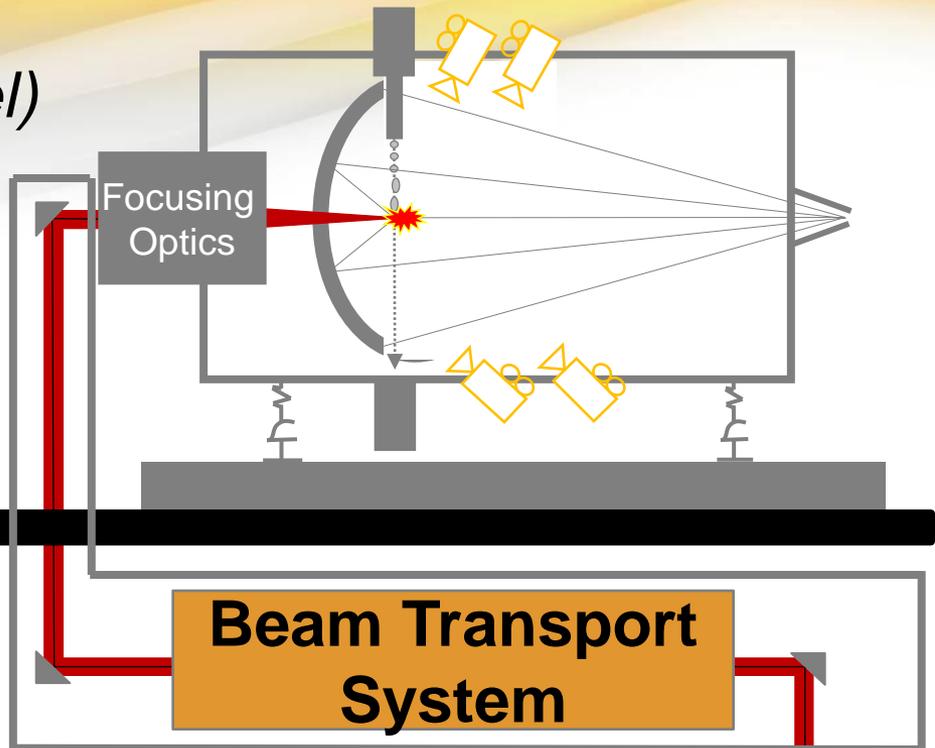
Progress Summary

- Total of 10 HVM I sources are installed and operational
 - 5 sources installed and exposing wafers at development fabs
 - 3 HVM I sources in San Diego for upgrade development , reliability enhancements, and for technology transfer to HVM II
 - 2 HVM I sources installed and operational at ASML
 - Collector lifetime of 45 billion (~4 months) reached in the field
 - SEMI E10 availability of sources in field approximately 60%
 - Field teams in place to support 24x7 operation globally
- HVM I power upgrade development in San Diego
 - Demonstrated 50W expose power at 40% duty cycle on HVM I source using pre-pulse, with full closed loop operation
 - 90% of dies <1% dose stability
- HVM II source program
 - First delivery to ASML completed
 - 4 sources in integration in San Diego
 - HVM II Drive Laser production ramping, 2 delivered, several more in build, with scheduled deliveries planned

Laser Produced Plasma Source Architecture

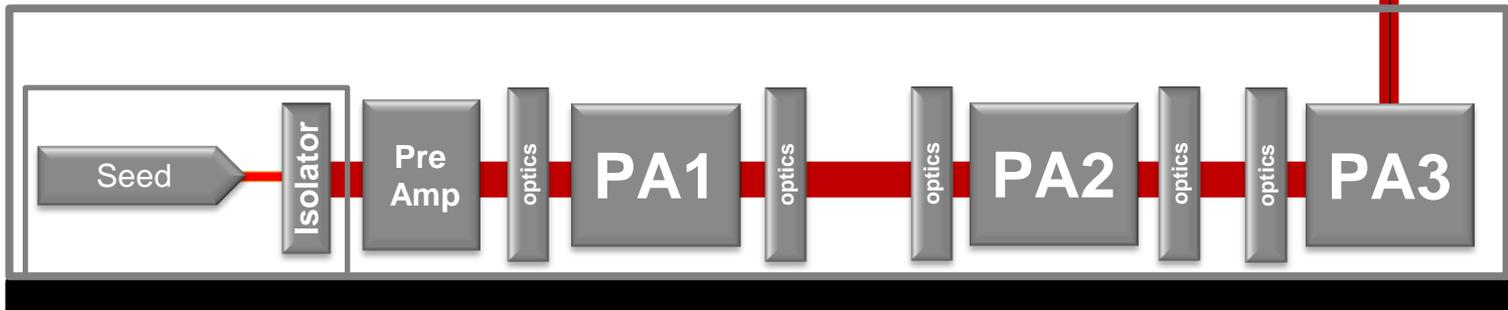
*Three Major Subsystems
(Drive Laser, BTS, Vessel)*

Vessel
With Collector, Droplet
Generator and Metrology



Fab Floor

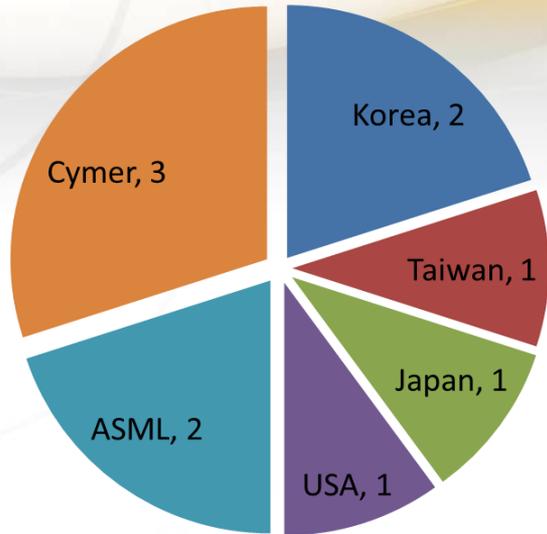
**Beam Transport
System**



Drive Laser

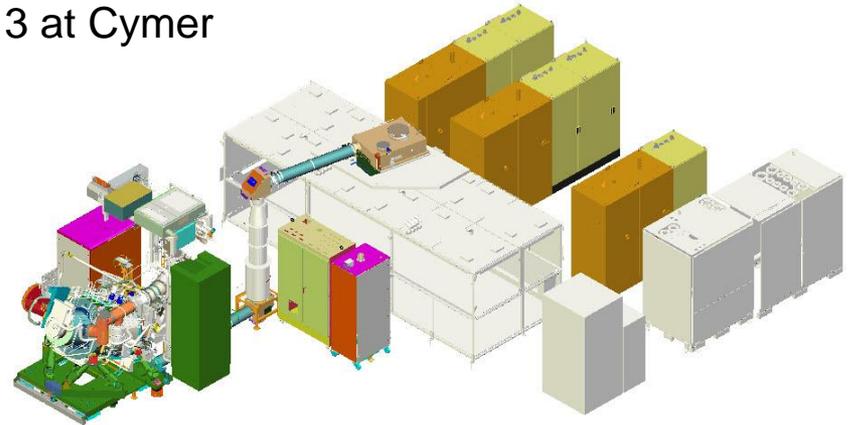
Sub-Fab Floor

Cymer Worldwide LPP Source Installed Base

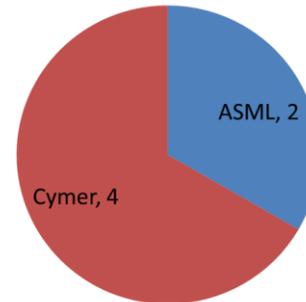
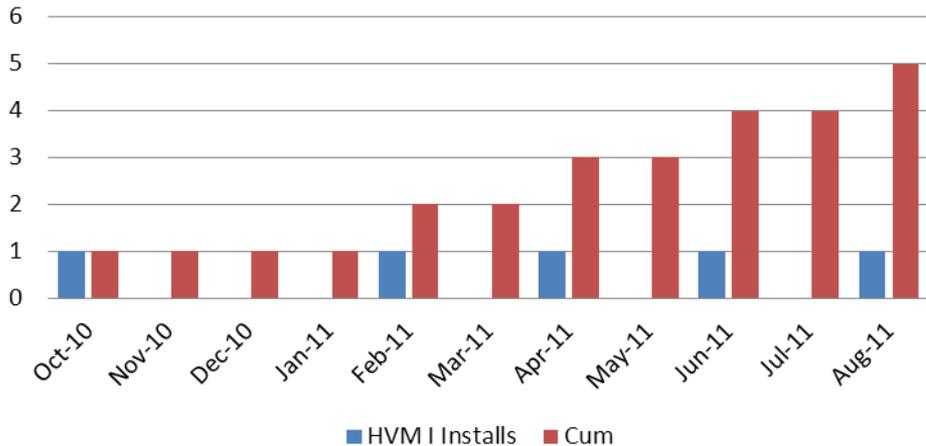


• 10 HVM I Sources installed and operational

- 5 at Chipmaker Fabs
- 2 at ASML
- 3 at Cymer



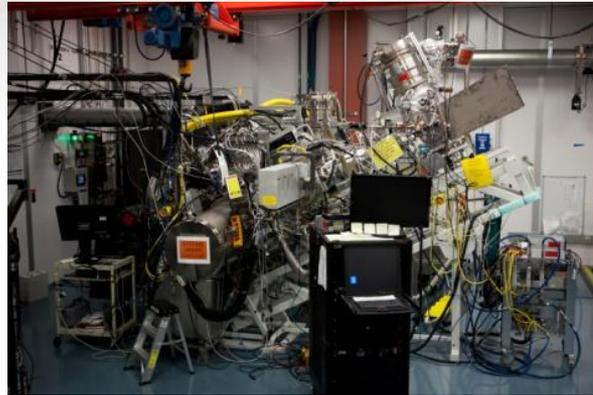
Chipmaker Installations



• First 6 HVM II Sources in progress

HVM I Sources for Prepulse Development

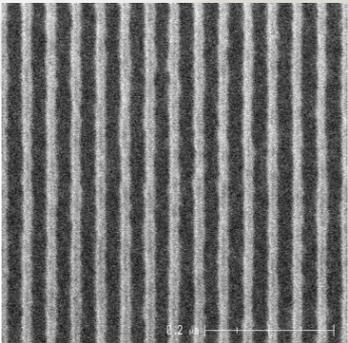
Internal Test Sources to Accelerate Power Roadmap



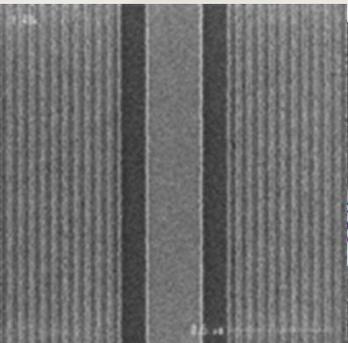
- Pilot 7, Dedicated R&D test source for Advanced Prepulse Development
- Pilot 8, Marathon runs using a scanner simulator to drive sequencing as if it were exposing wafers
 - Collector life-testing
 - Reliability testing
 - Upgrade to Prepulse in Q4
- Pilot 9, Dedicated Engineering test source for Prepulse deployment to the field and technology transfer to HVM II

Imaging Performance with LPP Sources on NXE:3100

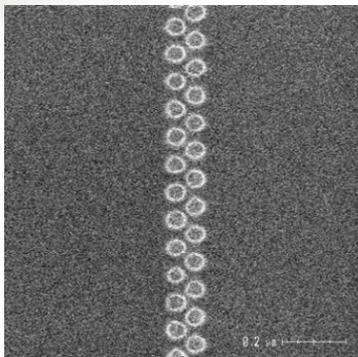
Enabling EUV Lithography



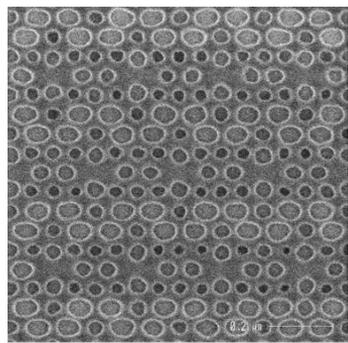
19 nm dense lines



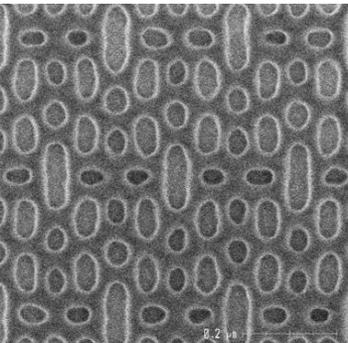
27 nm Gate Layer Flash



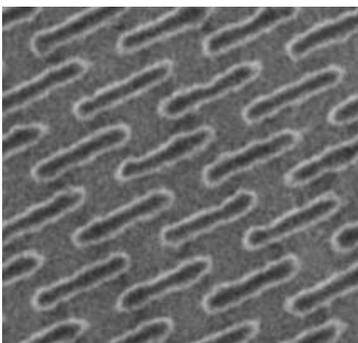
Flash staggered contact layer
Bitline pitch = 44 nm (1:1.2)
CH pitch = 74.4 nm



Sub 16 nm node SRAM Contact Hole
0.038 μ m² bit cell-size,
hp 30/32 nm



Sub 16 nm node SRAM metal-1
0.038 μ m² bit cell-size,
hp 30/32 nm



30 nm Brickwall DRAM

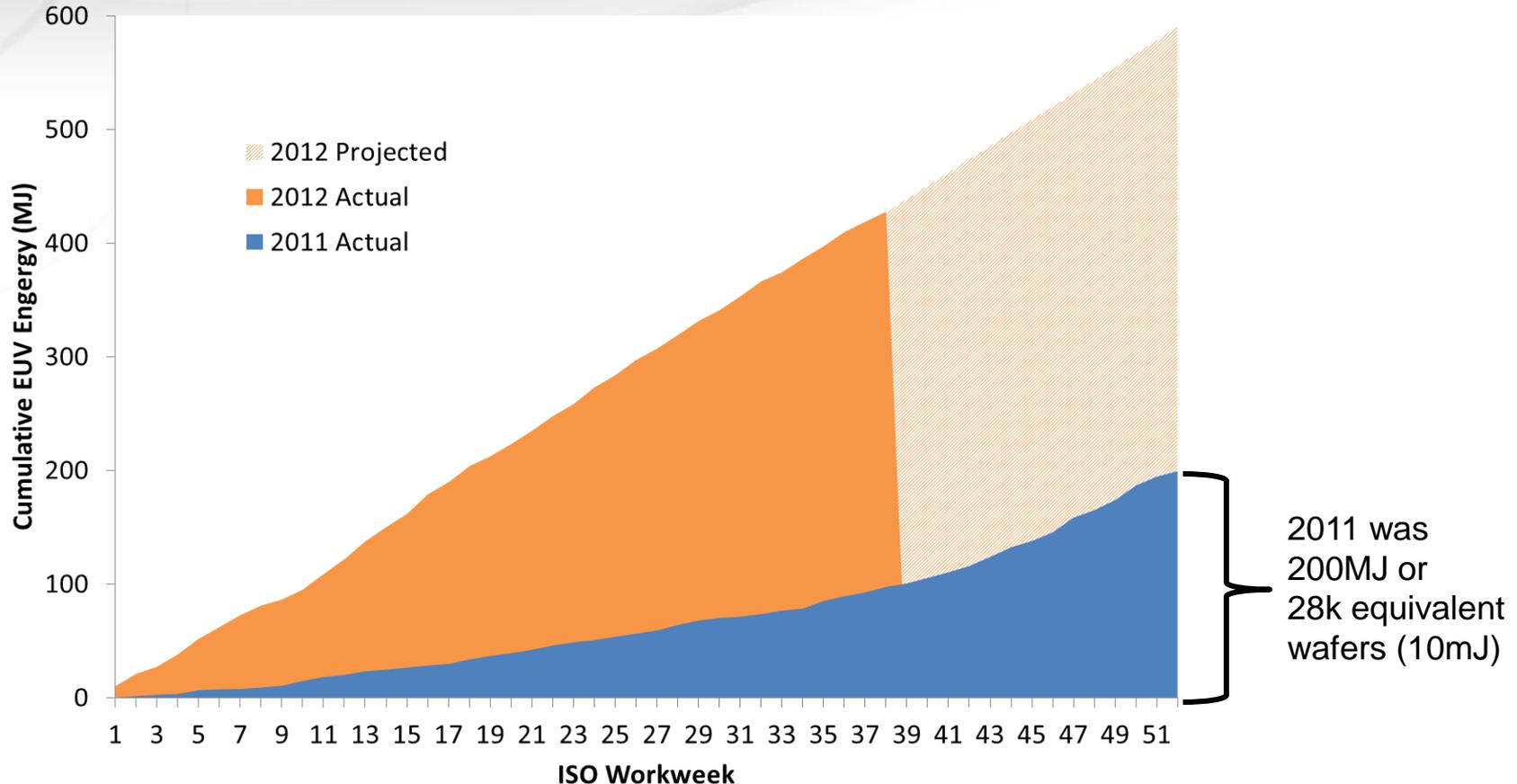
Courtesy of ASML



Total EUV Energy Produced: 2011, 2012

Cycles of Learning are Increasing Significantly

Cumulative EUV Energy: 2011, 2012



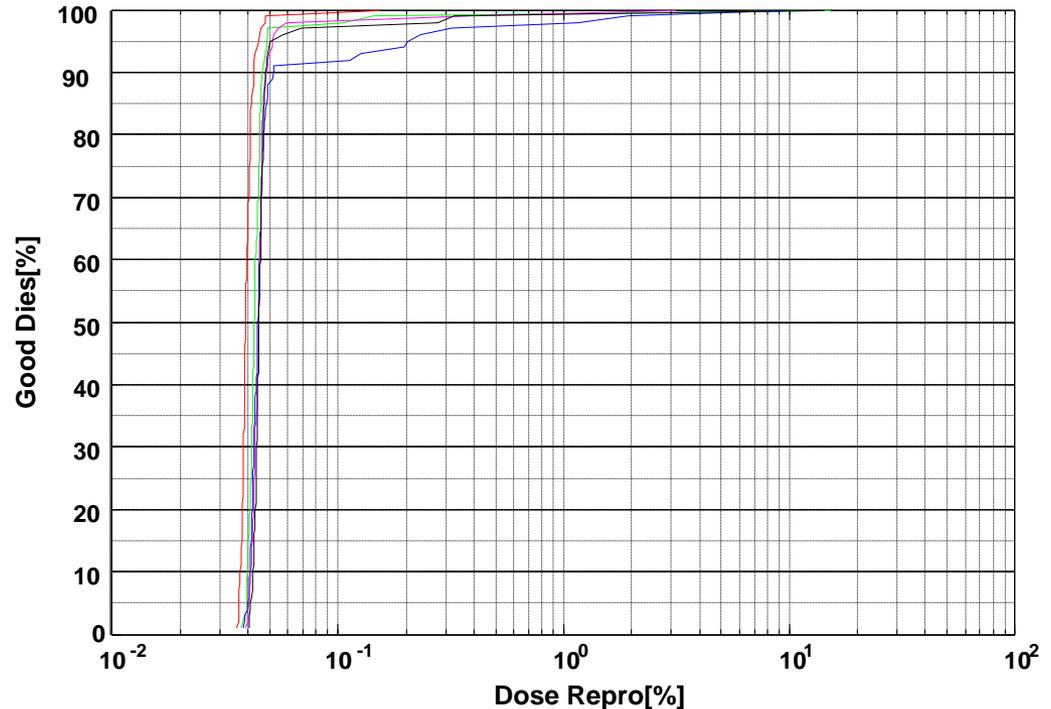
2012 YTD: ~430 MJ or 60,000 equivalent wafers (10mJ resist)

HVM I

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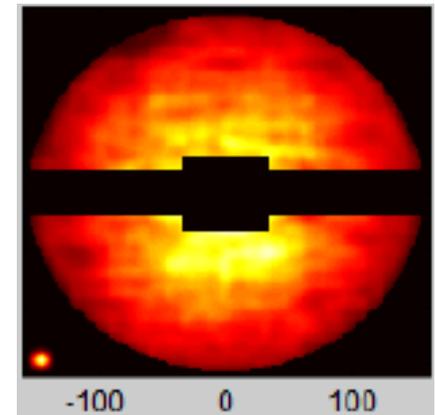
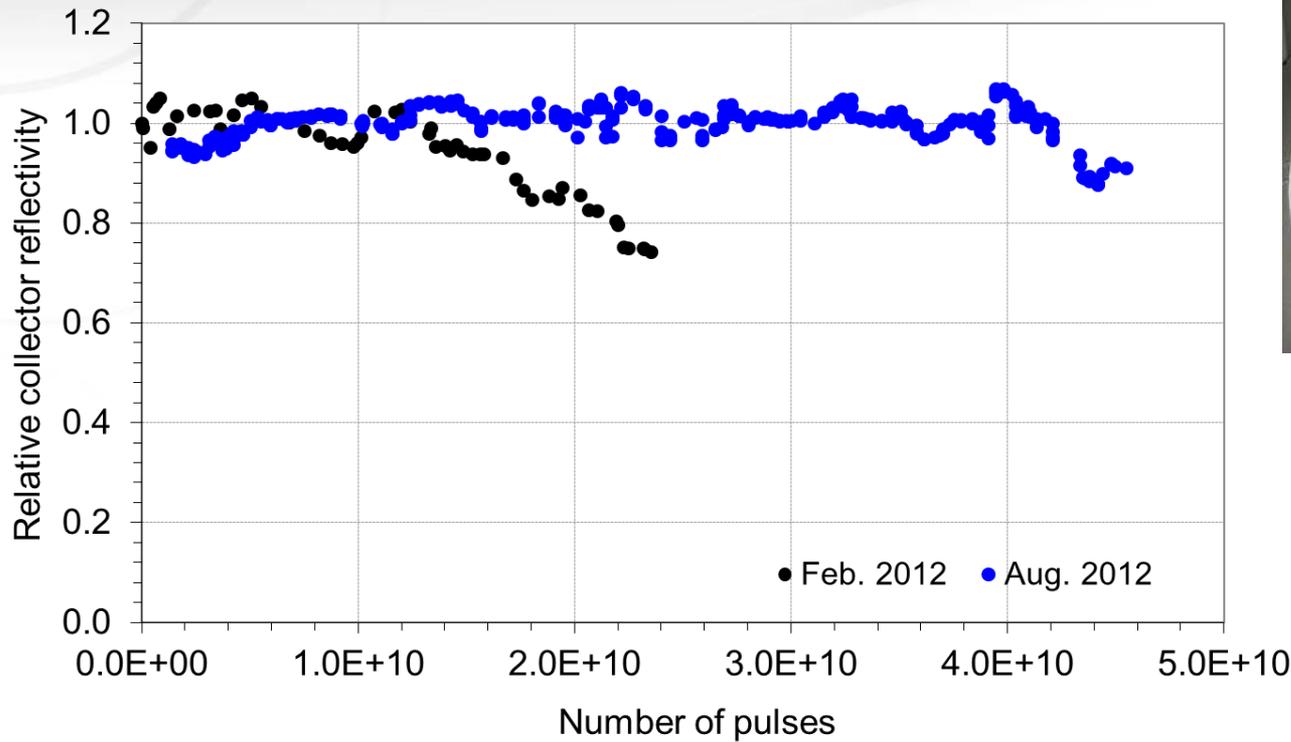
Current HVM I Performance in the Field

Typical Dose Stability in Field



- **~9-13 W** average exposure power is operational in the field
 - Capability for >100 wafers per day throughput
 - Better than $\pm 0.5\%$ dose stability on >99.7% of fields
- **60% Source Availability** (SEMI E10 Definition)
 - Down from 70% in previous quarters of 2012
- Controls: Closed loop operation for dose and plasma position control in three dimensions (e, x, y, z)
- Machine software: reduction of overhead time provided increased productivity

Improved Collector Lifetime in the Field: 45 x 10⁹ Pulses over 4 months of Operation



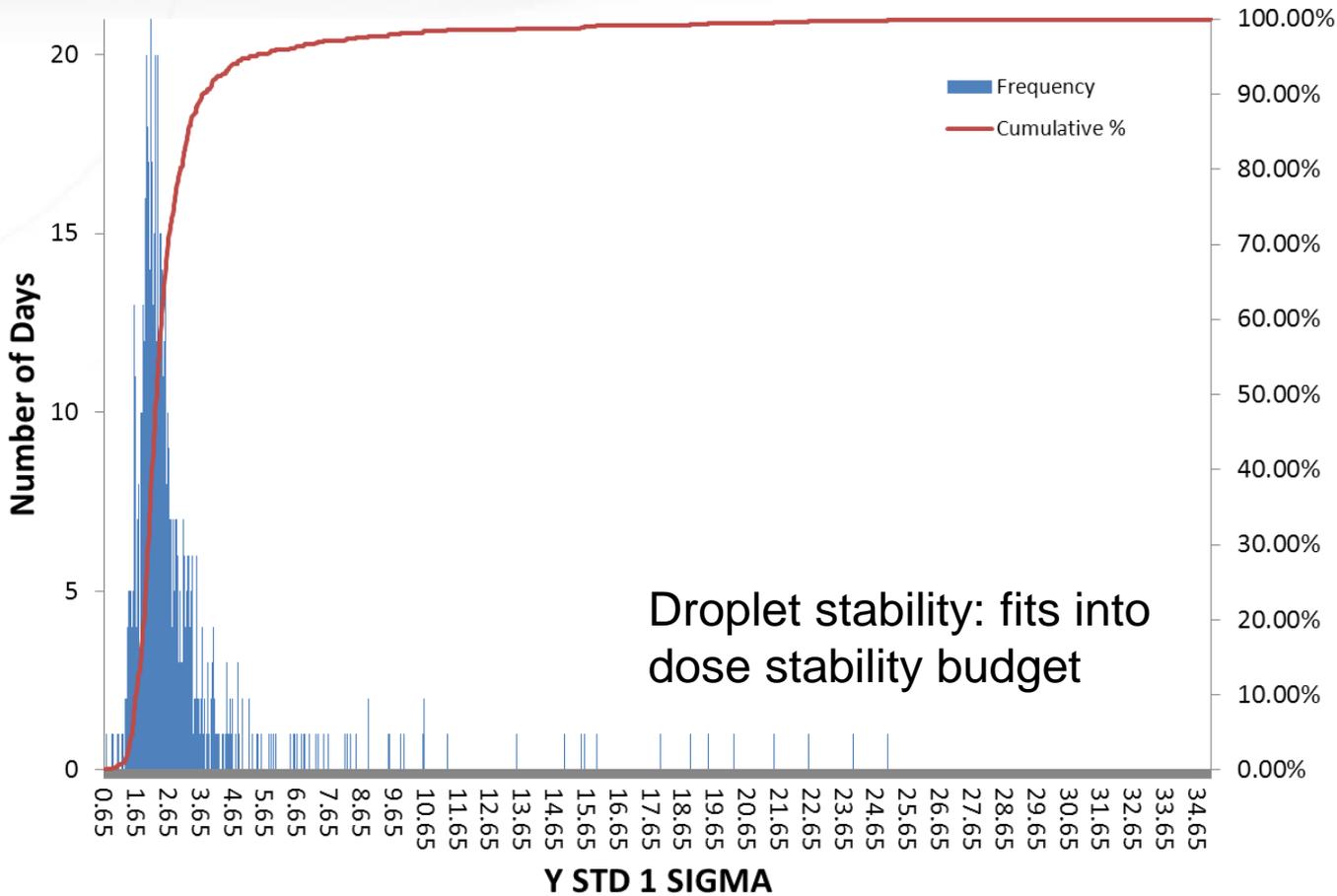
Far field image after 45 x 10⁹ pulses still looks good

EUV Image at
45 Billion Pulses

Droplet Position Stability of Five Sources Installed at Chipmaker Sites in 2012

Typical performance 80% <3.0 μ m

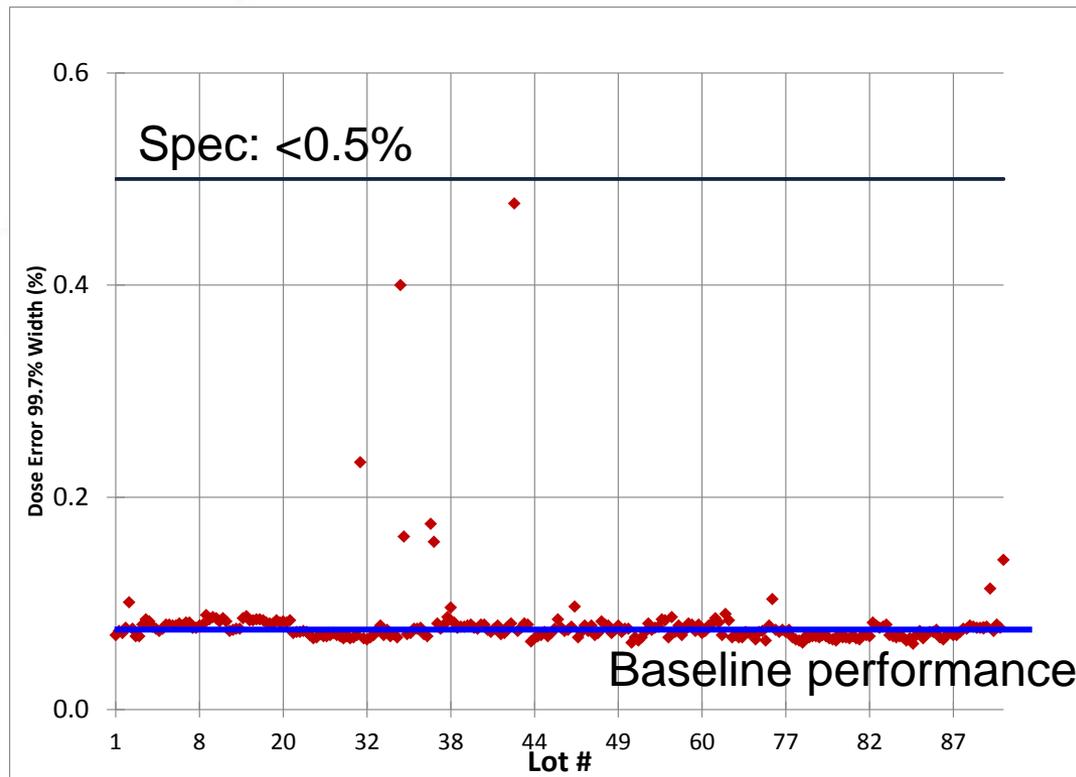
Droplet Stability of 5 Sources at Chipmaker Sites in 2012



2012 year to date

HVM I Dose Stability: Current Field Configuration

- Simulated exposure of ~500 wafers at ~13W
 - All meet wafer average dose error target
 - Only 1% of all wafers have individual fields above target



Each data point is one wafer

- Baseline dose stability performance is much better than specification
- Excursions can be eliminated by improving intrinsic stability or by applying controls

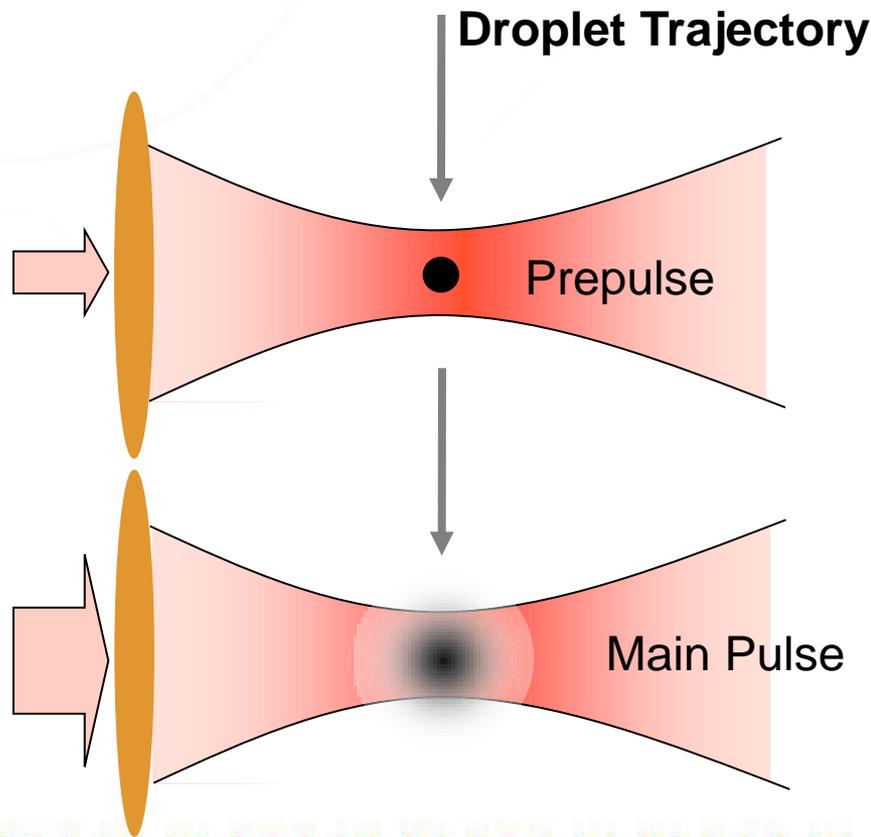
Prepulse

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Prepulse (Target Conditioning)

Conversion Efficiency Technology Improvement

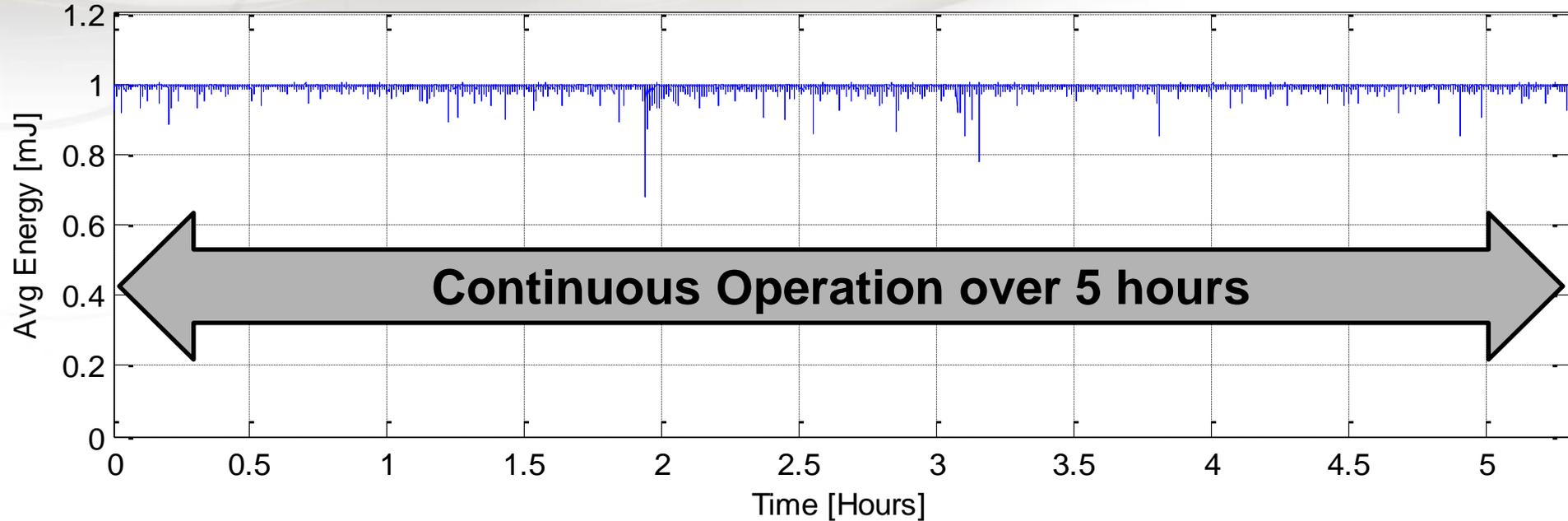
Scaling of EUV power requires increase in Conversion Efficiency (CE) – Prepulse has demonstrated this capability



Pre-pulse

- Pre-conditioning the droplet target by a pre-pulse is a demonstrated approach for CE scaling
 - Provides better matching of target size with focal region dimensions
- Preparing for deployment as an upgrade for HVM I and as the base configuration on HVM II

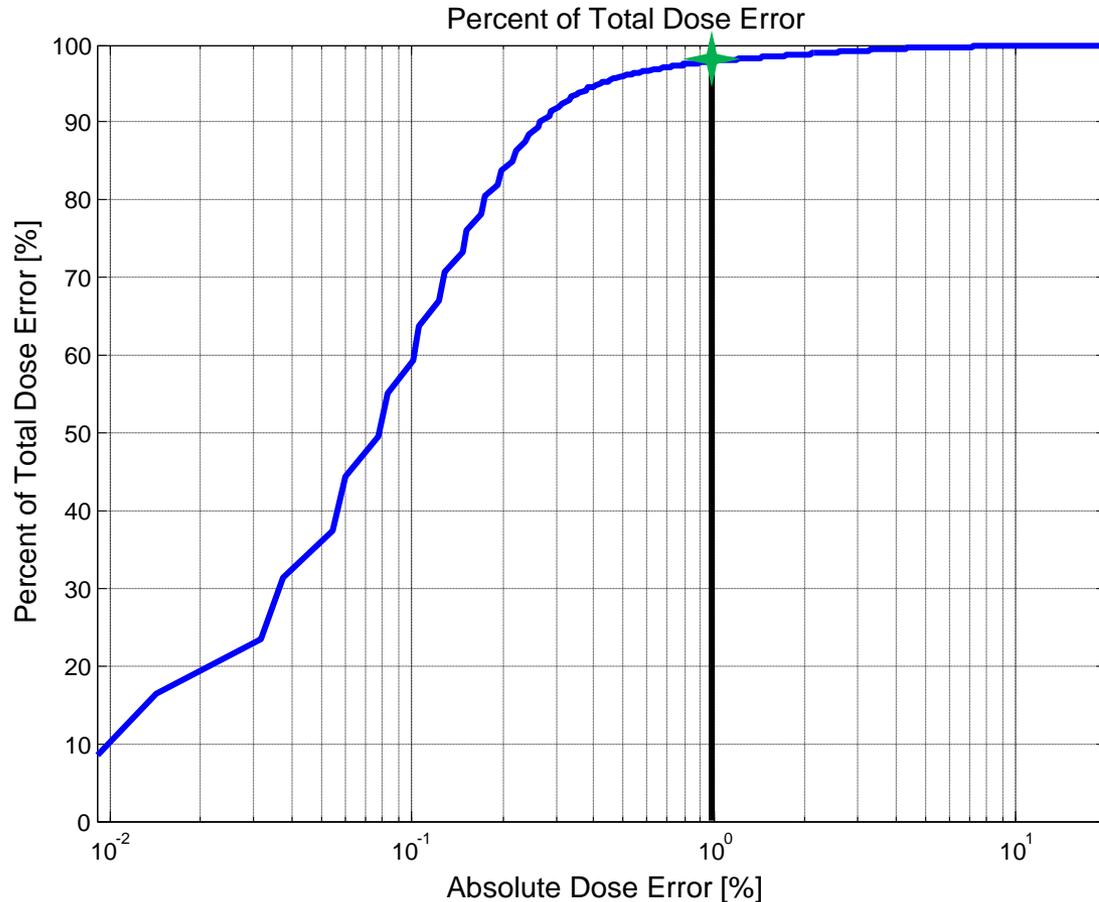
PrePulse Demonstrated with Closed Loop Control over 5 hours of Continuous Operation



- 50W in-burst dose-controlled power at 40% duty cycle
- Energy, timing, and plasma position in three dimensions under closed loop control (e, t, x, y, z)

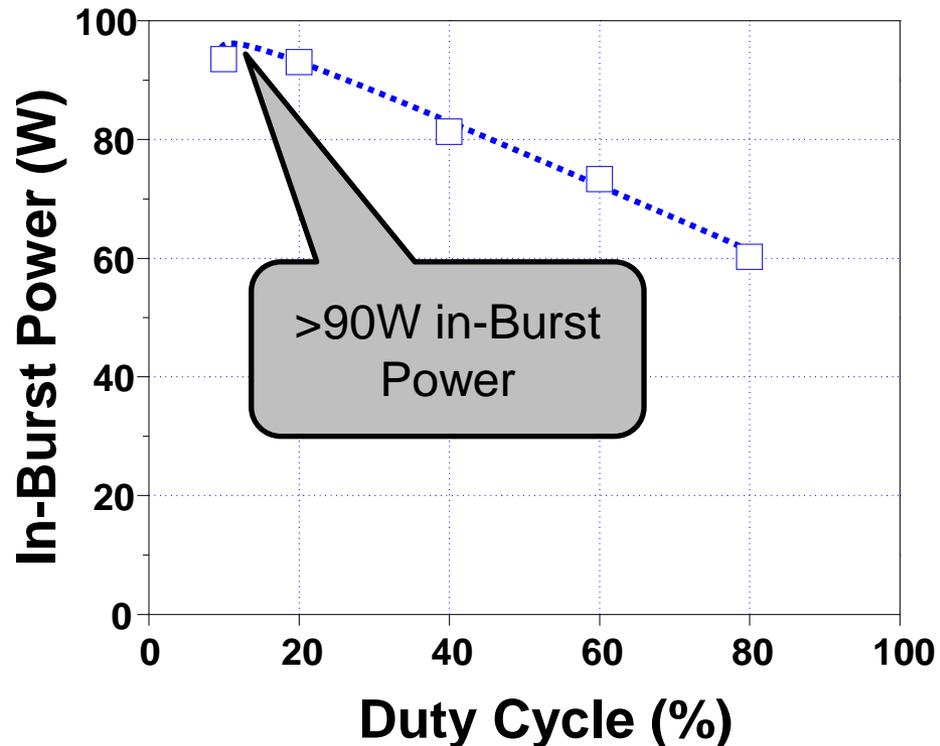
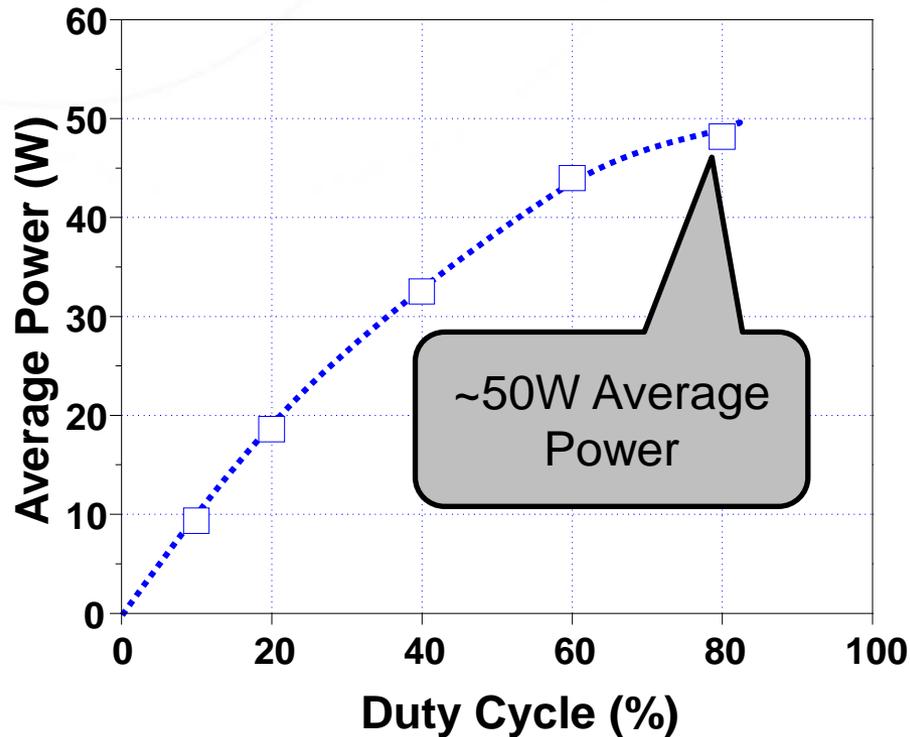
Dose Stability with Prepulse Demonstrated to Better than 90% of Dies $<1\%$ 3σ

- Dose stability is currently limited by dynamics of Prepulse targeting and motion control; improvements in both are planned



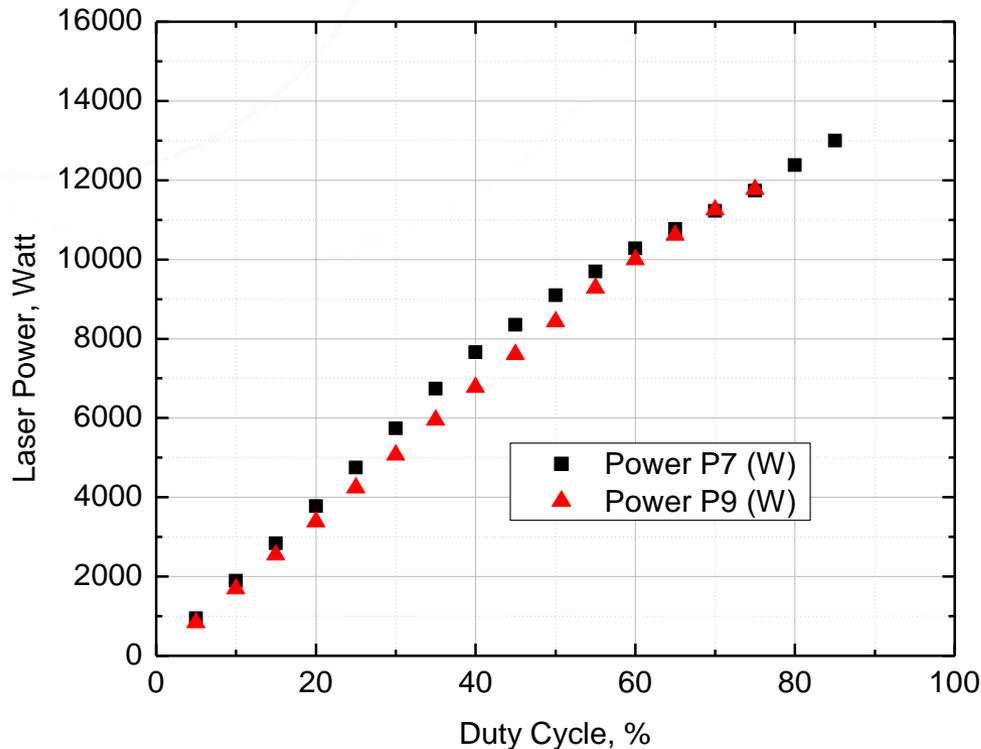
LPP with Prepulse: Capability up to ~50W Average Power at High Duty Cycle Demonstrated

- Prepulse technology demonstrated up to 90W in the burst at low duty cycle
- Power roll off remains a challenge

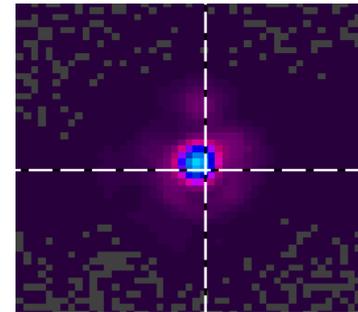


CO₂ Laser Power at High Duty Cycle Maintains Good Beam Quality

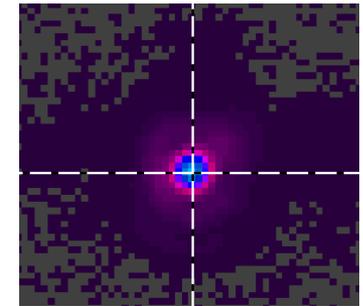
- Far-field beam quality remains relatively undistorted



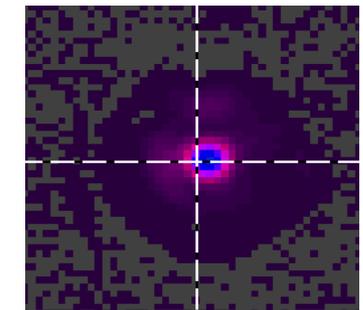
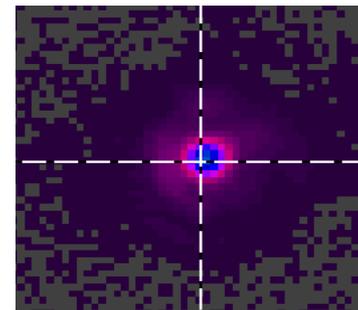
10% Duty Cycle



50% Duty Cycle

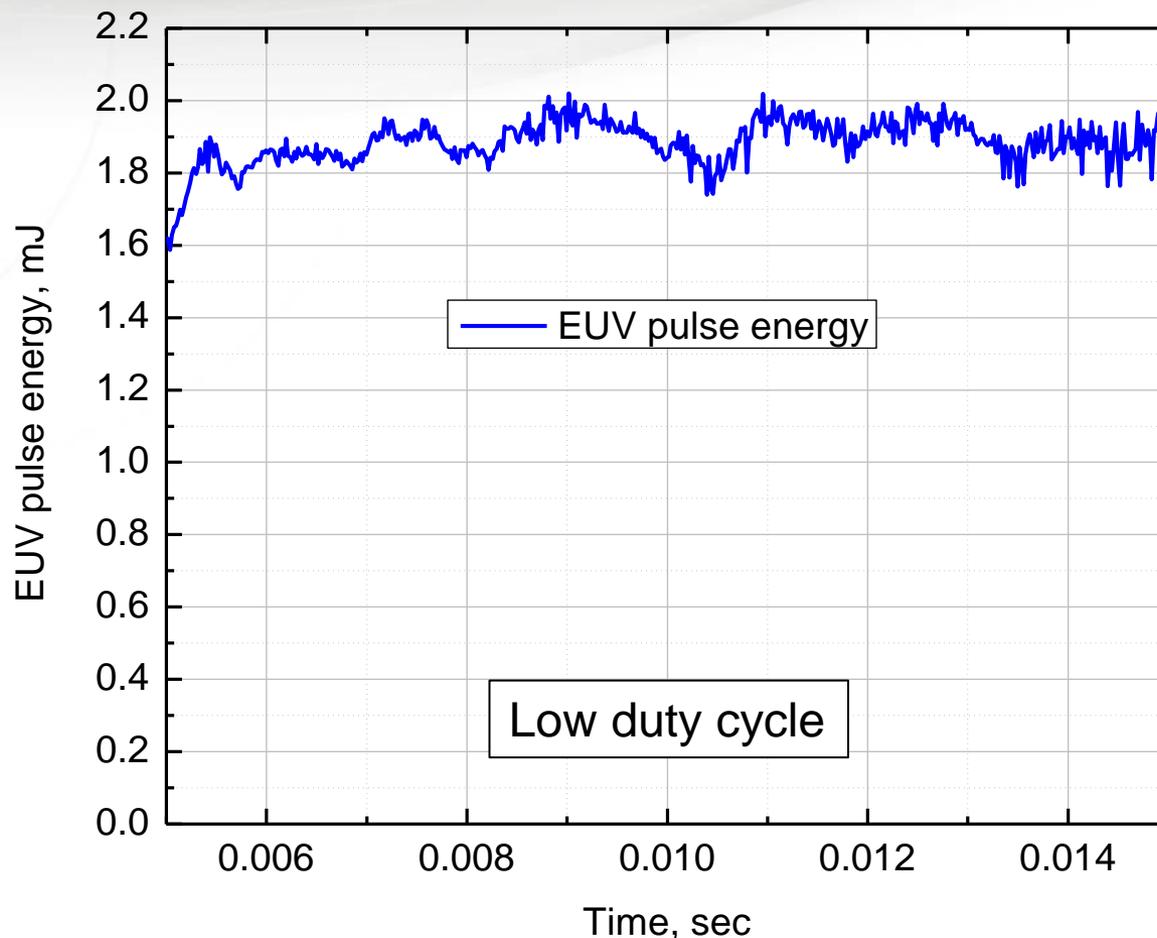


80% Duty Cycle



95% Duty Cycle

90W EUV Pulse Energy with Prepulse at 50 kHz Demonstrated on Internal Pilot Source

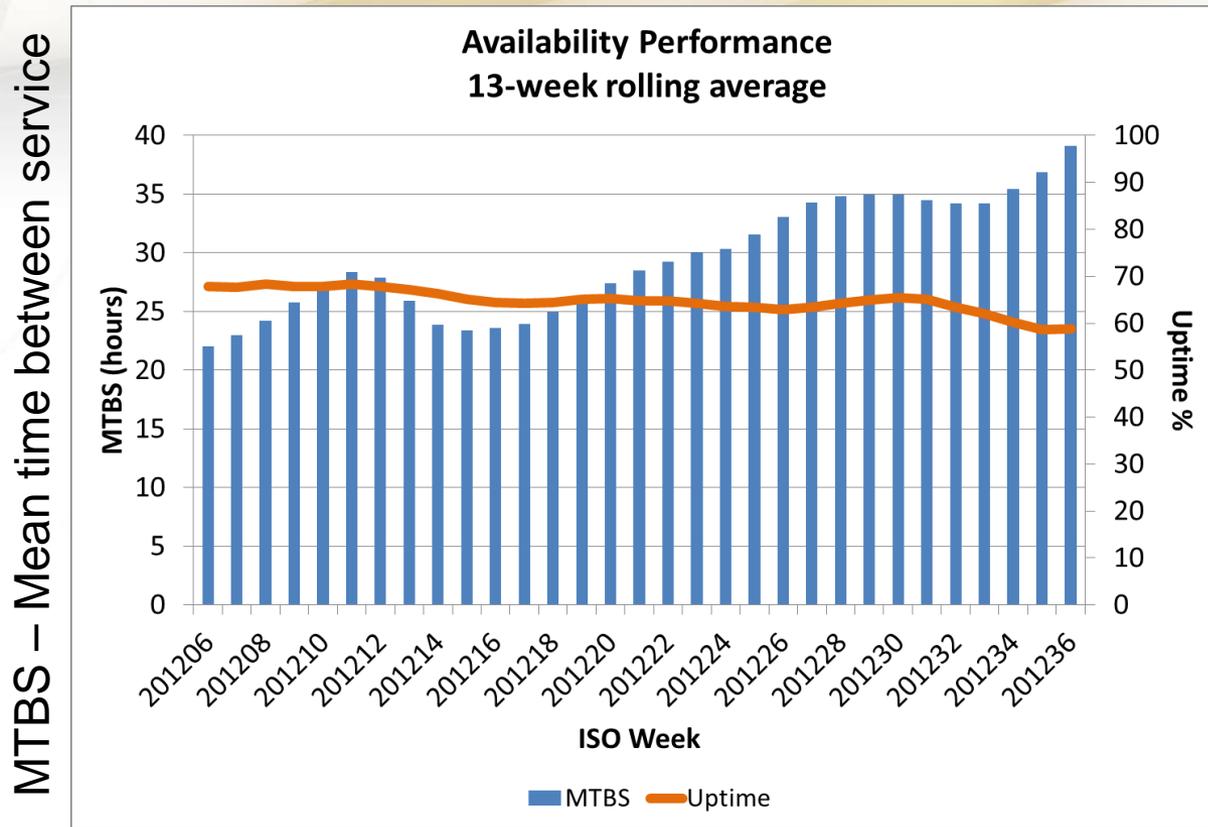


Prepulse development on internal pilot sources in San Diego making good progress

Availability

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Availability of HVM I Sources in Field (SEMI E10)



- Scheduled downtime primarily on three modules; Collector, Droplet Generator and Focusing System
- Uptime maintained above 60%, down from 70%; Recent dip in uptime due to two long down events

Scheduled Downtime Budget for HVM I:

Improvements Planned for both HVM I & HVM II

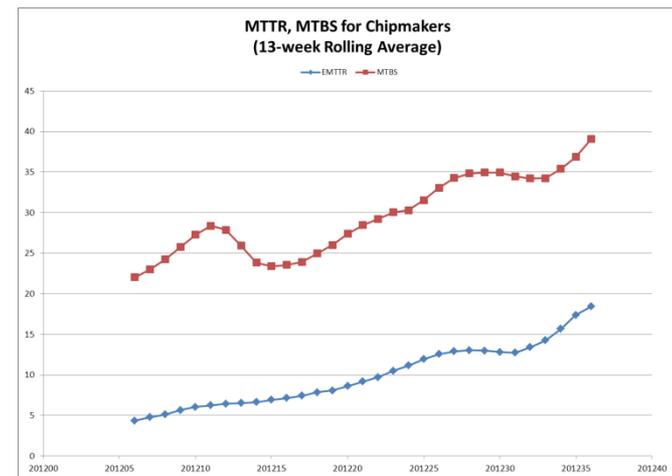
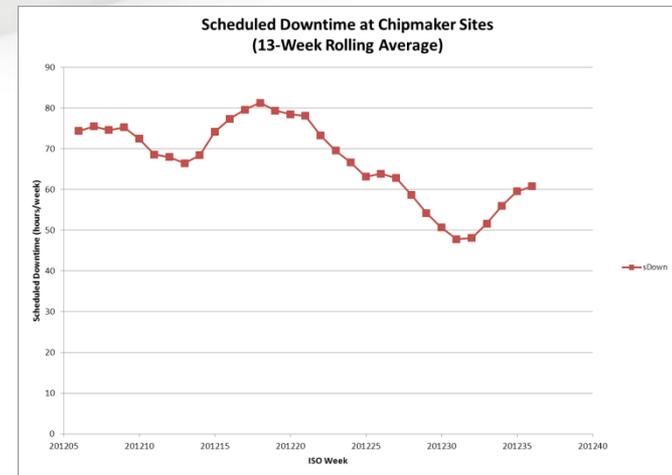
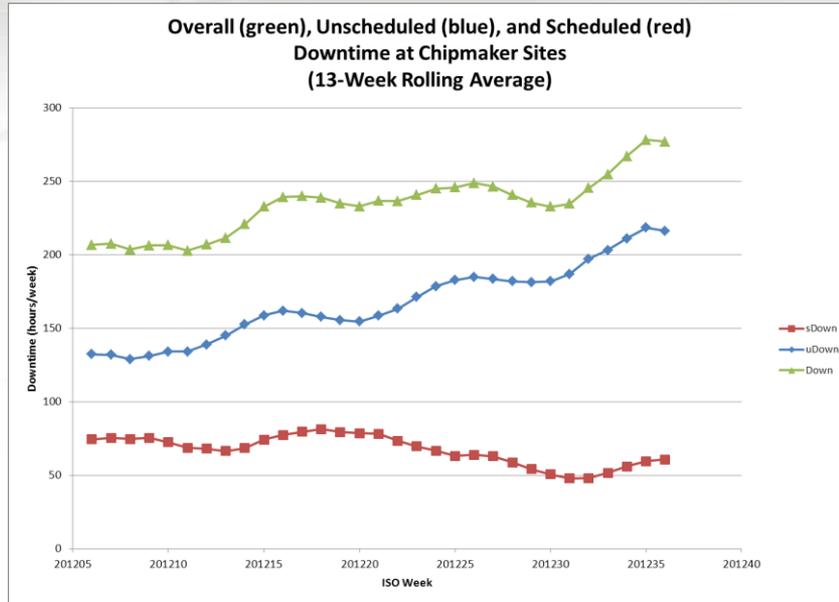
- Scheduled downtime increased with addition of Final Focus maintenance after upgrade to 60% duty cycle (10.6%)
- Improvements to all three modules prepared for HVM II
- Upgrades for HVM II will address both droplet generator and focusing system downtime

Scheduled Downtime

HVM I	MTBE (days)	MTTS (hours)	Downtime
Collector	60	115	7.5%
Droplet Generator	8.3	13	8.1%
Focus System	20	75	10.6%
Maintenance/Setup			4.2%
Other			6.0%
NET AVAILABILITY: 63.7%			

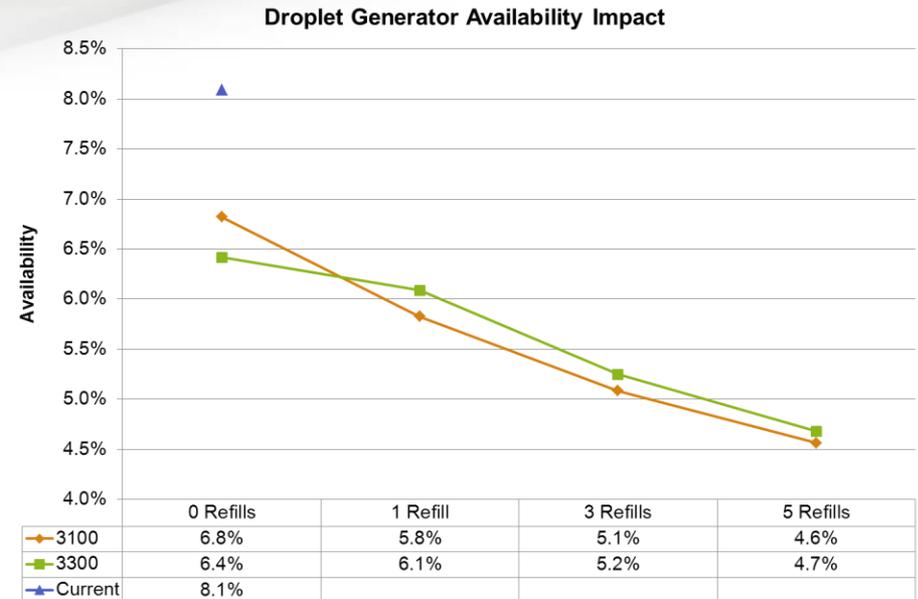
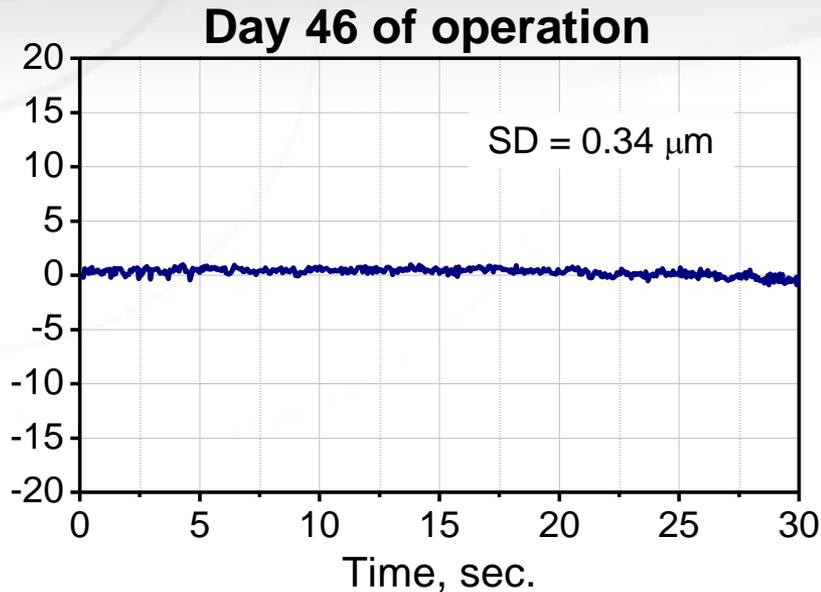
HVM II	MTBE (days)	MTTS (hours)	Downtime
Collector	67	12	0.7%
Droplet Generator	27	6	4.7%
Focus System	-	-	-%
Maintenance/Setup			4.2%
Other			6.0%
NET AVAILABILITY: 84.4%			

RAM Statistics for HVM I Sources at Chipmakers Sites (5 sites cumulative, 13 wk rolling average)



- Cymer Tactical Operations (TacOps) and Reliability Engineering track RAM and performance daily
- Customer data drives priority for continuous improvement projects

1100 Hrs Droplet Generator Operation with Refills Demonstrated (Reduced Scheduled Downtime)



- Extended operational lifetime using refill is being deployed to the field on HVM I sources
- Positive impact to availability increases with the number of refills



HVM II

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HVM II Source Integration in Process

- First HVM II sources are being integrated in San Diego and in Veldhoven



First HVM II Source Vessel

- The next 4 HVM II vessels are being prepared for test
- First 2 HVM II drive lasers are installed at ASML
- The next 3 HVM II drive lasers are in build at the supplier.

Manufacturing Capacity Expansion for HVM II Sources at Cymer and Suppliers



- Additional manufacturing space for integration and test of sources complete at Cymer and at suppliers

Path to Higher Power

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HVM I Source – 2012/2013 Power Upgrade Roadmap



Dedicated test source for prepulse

40-60 W Average Expose Power

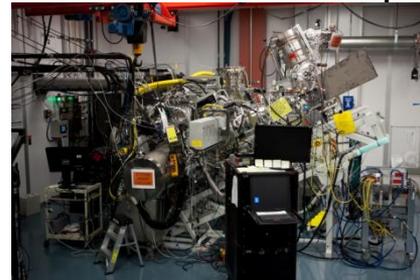
- $<\pm 0.5\%$ Dose Stability
- Continuous mode with pre-pulse

20W Average Expose Power

- $<\pm 0.5\%$ Dose Stability
- Burst mode, 90% duty cycle

9-13 W Average Expose Power

- $<\pm 0.5\%$ Dose Stability
- Burst mode, 60% duty cycle



Dedicated test source for 20W power

Now

Q4

Q2

available for the chipmaker

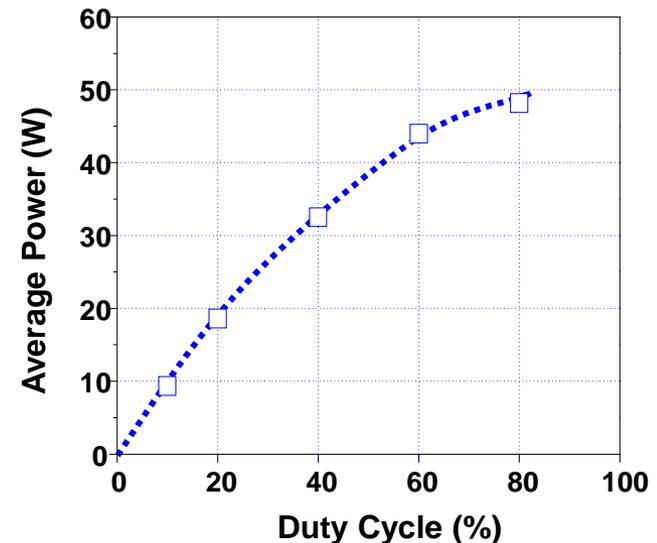
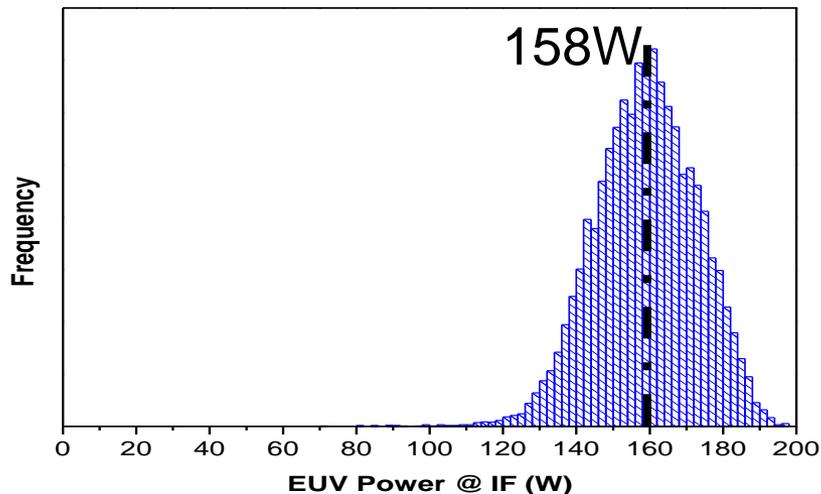
EUV Power Scaling Baseline

Low-Duty-Cycle Demonstration Status (LT1)

Expose power (calc.)	140W
Raw power (mean)	158W
Raw power	190W
CO ₂ power	24kW
Test length	>15min
Duty Cycle	3%

High-Duty-Cycle Demonstration Status (P7)

Expose power (calc.)	40W
Raw power (mean)	60W
Raw power (peak)	70W
CO ₂ power	17kW
Test length	~10min
Duty Cycle	80%



EUV Source Roadmap

2010

2011

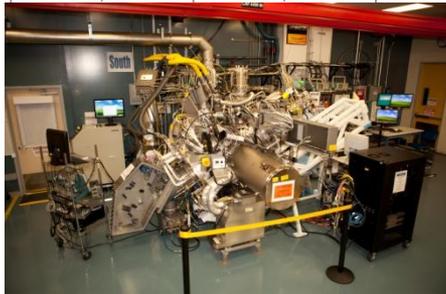
2012

2013

2014

2015

HVM I



HVM II

HVM I

- 10 sources in operation
- 5 installed at Fabs
- 5 for development at Cymer / ASML

HVM II

- 1st source delivered
- 4 in integration

EUV Source Power Roadmap

Source Model	HVM I	HVM II	HVM II	HVM II	HVM II
Average Laser Power (kW)	20	23	24	31	43
In-band CE (%)	2.0	2.0	2.5	2.5	3.0
Clean EUV Power (W)	60	80	125	160	250

Summary

- 10 HVM I sources are installed and operational, 5 at chipmaker fabs, 3 being used in San Diego for prepulse development and collector life testing, and 2 at ASML for scanner development
- HVM I source EUV average power in the field is 9-13W with better than $<0.5\%$ dose stability and capability of >100 wafers per day productivity
- Collector lifetime of 45 billion pulses (~ 4 months) achieved in the field
- Prepulse Development: 50W average power at 80% duty cycle demonstrated; up to 90W in-burst power at 20% duty cycle with 90% of dies $<1\%$ dose stability
- First HVM II source for ASML NXE 3300 scanner is delivered, integration of the next several are in process

Acknowledgements

Thank you!

Please see our
poster





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